## MC10E1652

## 5V, -5V Dual ECL Output Comparator with Latch

The MC10E1652 is fabricated using ON Semiconductor's advanced MOSAIC III process and is output compatible with 10 H logic devices. In addition, the device is available in a 20 -pin surface mount package. However, the MC10E1652 provides user programmable hysteresis.

The latch enable ( $\overline{\mathrm{LEN}_{\mathrm{a}}}$ and $\overline{\mathrm{LEN}_{\mathrm{b}}}$ ) input pins operate from standard ECL 10H logic levels. When the latch enable is at a logic high level, the MC 10 E 1652 acts as a comparator; hence, Q will be at a logic high level if $\mathrm{V} 1>\mathrm{V} 2(\mathrm{~V} 1$ is more positive than V 2$)$. Q is the complement of Q . When the latch enable input goes to a low logic level, the outputs are latched in their present state, providing the latch enable setup and hold time constraints are met. The level of input hysteresis is controlled by applying a bias voltage to the HYS pin.

## Features

- Typical 3.0 dB Bandwidth $>1.0 \mathrm{GHz}$
- Typical V to Q Propagation Delay of 775 ps
- Typical Output Rise/Fall of 350 ps
- Common Mode Range -2.0 V to +3.0 V
- Individual Latch Enables
- Differential Outputs
- Operating Mode: $\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.2 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}$
- Programmable Input Hysteresis
- No Internal Input Pulldown Resistors
- ESD Protection: Human Body Model; > 2 kV , Machine Model; > 100 V
- Meets or Exceeds JEDEC Spec EIA/JESD78 IC Latchup Test
- Moisture Sensitivity Level 3

For Additional Information, see Application Note AND8003/D

- Flammability Rating: UL $94 \mathrm{~V}-\mathrm{O} @ 0.125 \mathrm{in}$,

Oxygen Index: 28 to 34

- Transistor Count $=85$ devices
- These are $\mathrm{Pb}-$ Free Devices*

ORDERING INFORMATION
See detailed ordering and shipping information in the package dimensions section on page 7 of this data sheet.
ON Semiconductor ${ }^{\circledR}$
http://onsemi.com
 DIAGRAM

## 1652FNG

PLCC-20 FN SUFFIX
A = Assembly Location
YY = Year
WW = Work Week
$=\mathrm{Pb}-$ Free Package

[^0]
## MC10E1652



* All $\mathrm{V}_{\mathrm{CC}}$ and $\mathrm{V}_{\mathrm{CCO}}$ pins are NOT tied together on the die.

Warning: All $\mathrm{V}_{\mathrm{CC}}$, GND, and $\mathrm{V}_{\text {EE }}$ pins must be externally connected to Power Supply to guarantee proper operation.

Figure 1. Logic Diagrams and Pinout Assignments

$V_{\mathrm{EE}}=-5.2 \mathrm{~V}$
$\mathrm{V}_{\mathrm{CC}}=+5.0 \mathrm{~V}$
Figure 2. Logic Diagram

Table 1. PIN DESCRIPTION

| PIN | FUNCTION |
| :--- | :--- |
| Qa, $\overline{\text { Qa }}$ | ECL Differential Outputs (a) |
| Qb, $\overline{\text { Qb }}$ | ECL Differential Outputs (b) |
| LENa, LENb | ECL Latch Enable |
| V1a, V1b | Input Comparator 1 |
| V2a, V2b | Input Comparator 2 |
| HYS | Hysteresis Bias Voltage Control Input |
| VCC | Positive Supply |
| VEE $^{\text {NC }}$ | Negative Supply |
| GND | No Connect |

Table 2. FUNCTION TABLE

| $\overline{\text { LEN }}$ | V1, V2 | Function |
| :---: | :---: | :---: |
| H | V1 > V2 | H |
| H | $\mathrm{V} 1<\mathrm{V} 2$ | L |
| L | X | Latched |

Table 3. MAXIMUM RATINGS

| Symbol | Parameter | Condition 1 | Condition 2 | Rating | Units |
| :---: | :---: | :---: | :---: | :---: | :---: |
| VSUP | Total Supply Voltage | $\left\|\mathrm{V}_{\mathrm{EE}}\right\|+\left\|\mathrm{V}_{\mathrm{CC}}\right\|$ |  | 12.0 | V |
| VPP | Differential Input Voltage | \|V1 - V2| |  | 3.7 | V |
| $\mathrm{V}_{1}$ | Input Voltage |  |  | $\mathrm{V}_{\mathrm{EE}} \leq \mathrm{V}_{\mathrm{I}} \leq \mathrm{V}_{\mathrm{CC}}$ | V |
| $\mathrm{I}_{\text {out }}$ | Output Current | Continuous Surge |  | $\begin{gathered} 50 \\ 100 \end{gathered}$ | $\begin{aligned} & \mathrm{mA} \\ & \mathrm{~mA} \end{aligned}$ |
| $\mathrm{I}_{\mathrm{BB}}$ | $\mathrm{V}_{\text {BB }}$ Sink/Source |  |  | $\pm 0.5$ | mA |
| TA | Operating Temperature Range |  |  | 0 to +85 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {stg }}$ | Storage Temperature Range |  |  | -65 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\theta$ JA | Thermal Resistance (Junction to Ambient) | $\begin{aligned} & \hline 0 \text { LFPM } \\ & 500 \text { LFPM } \end{aligned}$ | $\begin{aligned} & 28 \text { PLCC } \\ & 28 \text { PLCC } \end{aligned}$ | $\begin{aligned} & 63.5 \\ & 43.5 \end{aligned}$ | $\begin{aligned} & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \end{aligned}$ |
| $\theta_{\text {JC }}$ | Thermal Resistance (Junction to Case) | std bd | 28 PLCC | 22 to 26 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\mathrm{V}_{\mathrm{EE}}$ | Operating Range | GND = 0 V |  | -4.2 to -5.7 | V |
| $\mathrm{T}_{\text {sol }}$ | Wave Solder Pb-Free | $\leq 3 \mathrm{sec} @ 260^{\circ} \mathrm{C}$ |  | 265 | ${ }^{\circ} \mathrm{C}$ |

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

Table 4. DC CHARACTERISTICS $\mathrm{V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \pm 5 \% ; \mathrm{V}_{\mathrm{EE}}=-5.2 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{CC}}=0 \mathrm{~V}$ (Note 1)

| Symbol | Characteristic | $0^{\circ} \mathrm{C}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage (Note 2) | -1020 |  | -840 | -980 |  | -810 | -920 |  | -735 | mV |
| $\mathrm{V}_{\text {OL }}$ | Output Low Voltage (Note 2) | -1950 |  | -1630 | -1950 |  | -1630 | -1950 |  | -1600 | mV |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage (LEN) | -1.95 |  | -1.48 | -1.95 |  | -1.48 | -1.95 |  | -1.45 | mV |
| $\mathrm{V}_{\text {IH }}$ | Input HIGH Voltage (LEN) | -1.17 |  | -0.84 | -1.13 |  | -0.81 | -1.07 |  | -0.735 | mV |
| $\begin{aligned} & \hline \mathrm{II} \\ & \mathrm{I}_{\mathrm{IH}} \end{aligned}$ | Input Current (V1, V2) Input HIGH Current (LEN) |  |  | $\begin{gathered} 65 \\ 150 \end{gathered}$ |  |  | $\begin{gathered} 65 \\ 150 \end{gathered}$ |  |  | $\begin{gathered} 65 \\ 150 \end{gathered}$ | $\mu \mathrm{A}$ |
| $\begin{array}{\|l} \hline \mathrm{I}_{\mathrm{CC}} \\ \mathrm{I}_{\mathrm{EE}} \\ \hline \end{array}$ | Positive Supply Current Negative Supply Current |  |  | $\begin{gathered} 50 \\ -55 \end{gathered}$ |  |  | $\begin{gathered} 50 \\ -55 \end{gathered}$ |  |  | $\begin{gathered} 50 \\ -55 \end{gathered}$ | mA |
| VCMR | Common Mode Range (Note 3) | -2.0 |  | 3.0 | -2.0 |  | 3.0 | -2.0 |  | 3.0 | V |
| Hys | Hysteresis (Note 4) |  | 27 |  |  | 27 |  |  | 30 |  | mV |
| $\mathrm{V}_{\text {skew }}$ | Hysteresis Skew (Note 5) |  | -1.0 |  |  | -1.0 |  |  | 0 |  | mV |
| $\mathrm{C}_{\text {in }}$ | Input Capacitance PLCC |  |  | 2 |  |  | 2 |  |  | 2 | pF |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

1. Input $V_{I L}$ and $V_{I H}$ parameters vary $1: 1$ with $V_{C C}$. Output $V_{O H}$ and $V_{O L}$ parameters vary $1: 1$ with GND.
2. Outputs are terminated through a 50 ohm resistor to GND-2 volts.
3. VCMR Min varies $1: 1$ with $\mathrm{V}_{\mathrm{EE}}$; Max varies $1: 1$ with $\mathrm{V}_{\mathrm{CC}}$.
4. The HYS pin programming characterization information is shown in Figure 2. The hysteresis values indicated in the data sheet are for the condition in which the voltage on the HYS pin is set to $\mathrm{V}_{\text {EE }}$.
5. Hysteresis skew ( $\mathrm{V}_{\text {skew }}$ ) is provided to indicate the offset of the hysteresis window. For example, at $25^{\circ} \mathrm{C}$ the nominal hysteresis value is 27 mV and the $\mathrm{V}_{\text {skew }}$ value indicates that the hysteresis was skewed from the reference level by 1 mV in the negative direction. Hence the hysteresis window ranged from 14 mV below the reference level to 13 mV above the reference level. All hysteresis measurements were determined using a reference voltage of 0 mV . The hysteresis skew values apply over the programming range shown in Figure 2.


Table 5. AC CHARACTERISTICS $\mathrm{V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \pm 5 \% ; \mathrm{V}_{\mathrm{EE}}=-5.2 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{\mathrm{CC}}=0 \mathrm{~V}$ (Note 6)

|  | Characteristic | $0^{\circ} \mathrm{C}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Symbol |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| $\mathrm{f}_{\text {MAX }}$ | Maximum Toggle Frequency |  | TBD |  |  | > 1.0 |  |  | TBD |  | GHz |
| $t_{\text {PLH }}$ <br> $t_{\text {PHL }}$ | Propagation Delay to Output (Note 7) <br> V to Q <br> LEN to Q | $\begin{aligned} & 750 \\ & 550 \end{aligned}$ | $\begin{aligned} & 900 \\ & 725 \end{aligned}$ | $\begin{gathered} 1050 \\ 900 \end{gathered}$ | $\begin{aligned} & 775 \\ & 550 \end{aligned}$ | $\begin{aligned} & 925 \\ & 750 \end{aligned}$ | $\begin{gathered} 1075 \\ 900 \end{gathered}$ | $\begin{aligned} & 850 \\ & 650 \end{aligned}$ | $\begin{gathered} 1025 \\ 825 \end{gathered}$ | $\begin{aligned} & 1200 \\ & 1000 \end{aligned}$ | ps |
| $\mathrm{t}_{\mathrm{s}}$ | Setup Time V | 450 | 300 |  | 450 | 300 |  | 550 | 350 |  | ps |
| $t_{h}$ | Enable Hold Time V | -50 | -250 |  | -50 | -250 |  | -100 | -250 |  | ps |
| $t_{\text {pw }}$ | Minimum Pulse Width | 400 |  |  | 400 |  |  | 400 |  |  | ps |
| $\mathrm{t}_{\text {skew }}$ | Within Device Skew (Note 8) |  | 15 |  |  | 15 |  |  | 15 |  | ps |
| $\mathrm{t}_{\text {JITTER }}$ | Cycle-to-Cycle Jitter |  | TBD |  |  | TBD |  |  | TBD |  | ps |
| $\mathrm{T}_{\text {DE }}$ | $\begin{aligned} & \text { Delay Dispersion } \\ & \qquad \begin{array}{r} \text { (ECL Levels) } \\ (\text { Notes } 910) \\ (\text { Notes } 9,11) \end{array} \end{aligned}$ |  |  |  |  | $\begin{gathered} 100 \\ 60 \end{gathered}$ |  |  |  |  | ps |
| $\mathrm{T}_{\mathrm{DL}}$ | $\begin{aligned} & \text { Delay Dispersion } \\ & \qquad \text { (TTL Levels) (Notes 12, 13) } \\ & \text { (Notes 11, 12) } \end{aligned}$ |  |  |  |  | $\begin{aligned} & 350 \\ & 100 \end{aligned}$ |  |  |  |  | ps |
| VPP | Differential Input Voltage $\quad\|\mathrm{V} 1-\mathrm{V} 2\|$ |  |  | 3.7 |  |  | 3.7 |  |  | 3.7 | V |
| $t_{r}$ $\mathrm{t}_{\mathrm{f}}$ | Rise/Fall Times (20-80\%) | 225 | 325 | 475 | 225 | 325 | 475 | 250 | 375 | 500 | ps |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
6. Input $\mathrm{V}_{\mathrm{IL}}$ and $\mathrm{V}_{\mathrm{IH}}$ parameters vary $1: 1$ with $\mathrm{V}_{\mathrm{CC}}$. Output $\mathrm{V}_{\mathrm{OH}}$ and $\mathrm{V}_{\mathrm{OL}}$ parameters vary $1: 1$ with GND.
7. The propagation delay is measured from the crosspoint of the input signal and the threshold value to the crosspoint of the $Q$ and $\bar{Q}$ output signals. For propagation delay measurements the threshold level $\left(V_{T H R}\right)$ is centered about an 850 mV input logic swing with a slew rate of $0.75 \mathrm{~V} / \mathrm{NS}$. There is an insignificant change in the propagation delay over the input common mode range.
8. $t_{\text {skew }}$ is the propagation delay skew between comparator $A$ and comparator $B$ for a particular part under identical input conditions.
9. Refer to Figure 4 and note that the input is at 850 mV ECL levels with the input threshold range between the $20 \%$ and $80 \%$ points. The delay is measured from the crosspoint of the input signal and the threshold value to the crosspoint of the Q and $\overline{\mathrm{Q}}$ output signals.
10. The slew rate is $0.25 \mathrm{~V} / \mathrm{NS}$ for input rising edges.
11. The slew rate is $0.75 \mathrm{~V} / \mathrm{NS}$ for input rising edges.
12. Refer to Figure 5 and note that the input is at 2.5 V TTL levels with the input threshold range between the $20 \%$ and $80 \%$ points. The delay is measured from the crosspoint of the input signal and the threshold value to the crosspoint of the $Q$ and $Q$ output signals.
13. The slew rate is $0.3 \mathrm{~V} / \mathrm{NS}$ for input rising edges.

## APPLICATIONS INFORMATION

The timing diagram (Figure 5.) is presented to illustrate the MC10E1652's compare and latch features. When the signal on the LEN pin is at a logic high level, the device is operating in the "compare mode," and the signal on the input arrives at the output after a nominal propagation delay ( $\mathrm{tPHL}^{2}$, $\left.\mathrm{t}_{\mathrm{PLH}}\right)$. The input signal must be asserted for a time, $\mathrm{t}_{\mathrm{s}}$, prior to the negative going transition on $\overline{\mathrm{LEN}}$ and held for a time, $t_{h}$, after the LEN transition. After time $t_{h}$, the latch is operating in the "latch mode," thus transitions on the input do not appear at the output. The device continues to operate in the "latch mode" until the latch is asserted once again. Moreover, the LEN pulse must meet the minimum pulse width ( $\mathrm{t}_{\mathrm{pw}}$ ) requirement to effect the correct input-output relationship. Note that the LEN waveform in Figure 5. shows the $\overline{\mathrm{LEN}}$ signal swinging around a reference labeled $\mathrm{VBB}_{\text {INT }}$; this waveform emphasizes the requirement that $\overline{\text { LEN }}$ follow typical ECL 10KH logic levels because
$\mathrm{VBB}_{\text {INT }}$ is the internally generated reference level, hence is nominally at the ECL VBB level.

Finally, $\mathrm{V}_{\mathrm{OD}}$ is the input voltage overdrive and represents the voltage level beyond the threshold level $\left(\mathrm{V}_{\mathrm{THR}}\right)$ to which the input is driven. As an example, if the threshold level is set on one of the comparator inputs as 80 mV and the input signal swing on the complementary input is from zero to 100 mV , the positive going overdrive would be 20 mV and the negative going overdrive would be 80 mV . The result of differing overdrive levels is that the devices have shorter propagation delays with greater overdrive because the threshold level is crossed sooner than the case of lower overdrive levels. Typically, semiconductor manufactures refer to the threshold voltage as the input offset voltage (VOS) since the threshold voltage is the sum of the externally supplied reference voltage and inherent device offset voltage.


Figure 5. Input/Output Timing Diagram

## MC10E1652

## DELAY DISPERSION

Under a constant set of input conditions comparators have a specified nominal propagation delay. However, since propagation delay is a function of input slew rate and input voltage overdrive the delay dispersion parameters, $\mathrm{T}_{\mathrm{DE}}$ and $\mathrm{T}_{\mathrm{DT}}$, are provided to allow the user to adjust for these variables (where $\mathrm{T}_{\mathrm{DE}}$ and $\mathrm{T}_{\mathrm{DT}}$ apply to inputs with standard ECL and TTL levels, respectively).

Figure 6. and Figure 7. define a range of input conditions which incorporate varying input slew rates and input voltage overdrive. For input parameters that adhere to these constraints the propagation delay can be described as:

$$
\mathrm{T}_{\mathrm{NOM}} \pm \mathrm{T}_{\mathrm{DE}}\left(\text { or } \mathrm{T}_{\mathrm{DT}}\right)
$$



Figure 6. ECL Dispersion Test Input Conditions
where $\mathrm{T}_{\text {NOM }}$ is the nominal propagation delay. $\mathrm{T}_{\text {NOM }}$ accounts for nonuniformity introduced by temperature and voltage variability, whereas the delay dispersion parameter takes into consideration input slew rate and input voltage overdrive variability. Thus a modified propagation delay can be approximated to account for the effects of input conditions that differ from those under which the parts where tested. For example, an application may specify an ECL input with a slew rate of $0.25 \mathrm{~V} / \mathrm{NS}$, an overdrive of 17 mV and a temperature of $25^{\circ} \mathrm{C}$, the delay dispersion parameter would be 100 ps . The modified propagation delay would be

$$
775 \mathrm{ps} \pm 100 \mathrm{ps}
$$



Figure 7. TTL Dispersion Test Input Conditions

## MC10E1652



Figure 8. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020 - Termination of ECL Logic Devices.)

## ORDERING INFORMATION

| Device | Package | Shipping $^{\dagger}$ |
| :--- | :--- | :---: |
| MC10E1652FNG | PLCC-20 <br> (Pb-Free) | 46 Units / Rail |
| MC10E1652FNR2G | PLCC-20 <br> (Pb-Free) | $500 /$ Tape \& Reel |

$\dagger$ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Resource Reference of Application Notes
AN1405/D - ECL Clock Distribution Techniques
AN1406/D - Designing with PECL (ECL at +5.0 V )
AN1503/D - ECLinPS ${ }^{\text {T }}$ I/O SPiCE Modeling Kit
AN1504/D - Metastability and the ECLinPS Family
AN1568/D - Interfacing Between LVDS and ECL
AN1672/D - The ECL Translator Guide
AND8001/D - Odd Number Counters Design
AND8002/D - Marking and Date Codes
AND8020/D - Termination of ECL Logic Devices
AND8066/D - Interfacing with ECLinPS
AND8090/D - AC Characteristics of ECL Devices

## 20 LEAD PLCC <br> CASE 775-02 ISSUE G

DATE 06 APR 2021

## SCALE 1:1




VIEW S

NOTES:

1. DIMENSIONS AND TOLERANCING PER ANSI Y14.5M, 1982.
2. DIMENSIONS IN INCHES.
3. DATUMS - L-, -M-, AND -N- DETERMINED WHERE TOP OF LEAD SHOULDER EXITS PLASTIC BODY AT MOLD PARTING LINE.
4. DIMENSION G1, TRUE POSITION TO BE MEASURED AT DATUM -T-, SEATING PLANE.
5. DIMENSIONS R AND U DO NOT INCLUDE MOLD FLASH. ALLOWABLE MOLD FLASH IS 0.010 (0.250) PER SIDE.
6. DIMENSIONS IN THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO 0.012 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY
EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE
BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY
MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY
7. DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635)

|  | INCHES |  | MILLIMETERS |  |
| :---: | :---: | :---: | :---: | :---: |
| DIM | MIN | MAX | MIN | MAX |
| A | 0.385 | 0.395 | 9.78 | 10.03 |
| B | 0.385 | 0.395 | 9.78 | 10.03 |
| C | 0.165 | 0.180 | 4.20 | 4.57 |
| E | 0.090 | 0.110 | 2.29 | 2.79 |
| F | 0.013 | 0.021 | 0.33 | 0.53 |
| G | 0.050 BSC |  | 1.27 |  |
| BSC |  |  |  |  |
| H | 0.026 | 0.032 | 0.66 | 0.81 |
| J | 0.020 | --- | 0.51 | --- |
| K | 0.025 | --- | 0.64 | --- |
| R | 0.350 | 0.356 | 8.89 | 9.04 |
| U | 0.350 | 0.356 | 8.89 | 9.04 |
| V | 0.042 | 0.048 | 1.07 | 1.21 |
| W | 0.042 | 0.048 | 1.07 | 1.21 |
| $\mathbf{X}$ | 0.042 | 0.056 | 1.07 | 1.42 |
| Y | --- | 0.020 | --- | 0.50 |
| Z | $2^{\circ}$ | $10^{\circ}$ | $2{ }^{\circ}$ | $10^{\circ}$ |
| G1 | 0.310 | 0.330 | 7.88 | 8.38 |
| K1 | 0.040 | --- | 1.02 | --- |

GENERIC MARKING DIAGRAM*


XXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
YY = Year
WW = Work Week
$\mathrm{G} \quad=\mathrm{Pb}-$ Free Package
*This information is generic. Please refer to device data sheet for actual part marking. $\mathrm{Pb}-$ Free indicator, " G " or microdot " $\stackrel{\mathrm{*}}{ }$ ", may or may not be present.

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| ---: | :--- | :--- | :--- |
| DESCRIPTION: | 20 LEAD PLCC | PAGE 1 OF 1 |

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LM2903M/TR LM2903F-E2 MCP6544-EP MCP6542T-E/MS LM2901EDR2G TS391SN2T1G LM111JG LM239APT HMC675LC3CTR 5962-8765801PA MAX9024AUD+ LT6700HVIS6-2\#TRMPBF 5962-8765902CA ADCMP394ARZ-RL7 LM339AMX LTC1440IMS8\#PBF AZV331KSTR-G1 LTC1841IS8\#PBF LTC1440CN8\#PBF LTC1542CS8\#PBF LTC1445CS\#PBF TL331VSN4T3G LT6700IDCB1\#TRMPBF LTC1042CN8\#PBF LTC1540CMS8\#PBF LT6703CDC-2\#TRMPBF ADCMP607BCPZ-R7 LT1720CDD\#PBF LTC1040CN\#PBF LT6700MPDCB-1\#TRMPBF LT6700IDCB-3\#TRMPBF LTC1440IS8\#PBF S-89431ACNC-HBVTFG CMP402GSZREEL NTE1718 NTE943 NTE943M NTE943SM TA75S393F,LF(T ALD2301APAL


[^0]:    *For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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